**601 McCarthy Blvd**

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***Failure Analysis & Corrective Action Report***

***\*Final\****

**RMA Number:** Click here to enter text. **Device:**Click here to enter text.

|  |  |
| --- | --- |
| **Date:** Click here to enter a date. | **Author:** Click here to enter text. |

**Customer Information:**

**Name:** Click here to enter text.

### Customer Failure Environment

|  |  |  |
| --- | --- | --- |
| **Type of Failure:** Click here to enter text. | **Nature of Test:** Click here to enter text. | **Failure Description:** Click here to enter text. |
|  |  |  |
|  |  |  |
| **Failing Temperature:** Click here to enter text. | **DOS Image:** Click here to enter text. | **Does Good Unit Pass Test:** Click here to enter text. |
|  |  |  |
|  |  |  |
| **Parts Received Date:** Click here to enter a date. |  |  |
|  |  |  |

**Problem Description:**

**Customer Issue Description:** Click here to enter text.

### Device Details: Click here to enter text.

**Summary:**

The returned units were confirmed to be unrecognized and were found to be unable to produce valid card identification data. Analysis on the returned units confirmed them to have signs of mechanical damage on the external package, which is indicative of mechanical overstress or improper handling during field usage. The units are considered to be failing due to mechanically stress induced internal circuitry damage which occurred after shipment from SanDisk.

**Team Members:**

Name: Click here to enter text. Title: Click here to enter text.

**Root Cause Analysis Summary:**

**Failure Analysis Results:**

Upon return, the units were visually inspected and confirmed to have Click here to enter text. (heavy scratches, etc) and other signs of mechanical wear/damage on their external packages.

At the application level, the units were confirmed to be unrecognized. They failed to display valid unit identification register data.

The units were then tested in a diagnostic host, where they also failed to initialize. With this, further testing at the card level was not possible.

**Root Cause Concusions:**

Based on the analysis above, the units are believed to have failed due to internal circuitry damage. Such damage is expected to be the result of mechanical overstress or improper handling during field usage.